

| L Number | Hits | Search Text | DB | Time stamp |
|----------|-------|--|---|---------------------|
| 1 | 9 | ((compar\$3 or discriminat\$3 or differen\$5) same (label\$3 or categoriz\$3 or tag\$4 or mark\$3 or indicat\$3)) and ((label\$3 or categoriz\$3 or tag\$4 or mark\$3 or indicat\$3) and ((leaf or relat\$3 or depend\$4) near2 (cell or portion)) and (((compar\$3 or discriminat\$3 or differen\$5) with (resistance or capacitance or impedance or power) with (threshold or constraint or standard or predetermin\$5)) and (((compar\$3 or discriminat\$3 or differen\$5) same (resistance or capacitance or impedance or power) same (threshold or constraint or standard or predetermin\$5)) and (((compar\$3 or discriminat\$3 or differen\$5) same (resistance or capacitance or impedance or power)) and (((compar\$3 or discriminat\$3 or differen\$5) same (worst or pessimistic or maximum or max) same (optimistic or minimum or min)) and (((IC or (integrated adj1 circuit) or circuit or VLSI or LSI) same (design\$3 or model\$3 or similat\$3)) and ((worst or pessimistic or maximum or max) same (optimistic or minimum or min))))))) and ((replac\$3 or displac\$3 or supersed\$3 or supplant\$3) with (cell or portion or circuit or unit or block or cluster)) | USPAT; US-PGPUB; EPO; JPO; DERWENT | 2004/02/04 12:46 |
| 2 | 32 | (label\$3 or categoriz\$3 or tag\$4 or mark\$3 or indicat\$3) and ((leaf or relat\$3 or depend\$4) near2 (cell or portion)) and (((compar\$3 or discriminat\$3 or differen\$5) with (resistance or capacitance or impedance or power) with (threshold or constraint or standard or predetermin\$5)) and (((compar\$3 or discriminat\$3 or differen\$5) same (resistance or capacitance or impedance or power) same (threshold or constraint or standard or predetermin\$5)) and (((compar\$3 or discriminat\$3 or differen\$5) same (resistance or capacitance or impedance or power)) and (((compar\$3 or discriminat\$3 or differen\$5) same (worst or pessimistic or maximum or max) same (optimistic or minimum or min)) and (((IC or (integrated adj1 circuit) or circuit or VLSI or LSI) same (design\$3 or model\$3 or similat\$3)) and ((worst or pessimistic or maximum or max) same (optimistic or minimum or min)))))) | USPAT; US-PGPUB; EPO; JPO; DERWENT | 2004/02/04 12:50 |
| - | 33606 | ((IC or (integrated adj1 circuit) or circuit or VLSI or LSI) same (design\$3 or model\$3 or similat\$3)) and ((worst or pessimistic or maximum or max) same (optimistic or minimum or min)) | USPAT; US-PGPUB; EPO; JPO; DERWENT | 2004/02/04 07:56 |
| - | 9987 | ((compar\$3 or discriminat\$3 or differen\$5) same (worst or pessimistic or maximum or max) same (optimistic or minimum or min)) and (((IC or (integrated adj1 circuit) or circuit or VLSI or LSI) same (design\$3 or model\$3 or similat\$3)) and ((worst or pessimistic or maximum or max) same (optimistic or minimum or min)))) | USPAT; US-PGPUB; EPO; JPO; DERWENT | 2004/02/04 07:57 |

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| - | 5648 | ((compar\$3 or discriminat\$3 or differen\$5) same (resistance or capacitance or impendance or power)) and (((compar\$3 or discriminat\$3 or differen\$5) same (worst or pessimistic or maximum or max) same (optimistic or minimum or min)) and (((IC or (integrated adj1 circuit) or circuit or VLSI or LSI) same (design\$3 or model\$3 or similat\$3)) and ((worst or pessimistic or maximum or max) same (optimistic or minimum or min)))))) | USPAT; US-PGPUB; EPO; JPO; DERWENT | 2004/02/04 07:59 |
| - | 1953 | ((compar\$3 or discriminat\$3 or differen\$5) same (resistance or capacitance or impendance or power) same (threshold or constraint or standard or predetermin\$5)) and (((compar\$3 or discriminat\$3 or differen\$5) same (resistance or capacitance or impendance or power)) and (((compar\$3 or discriminat\$3 or differen\$5) same (worst or pessimistic or maximum or max) same (optimistic or minimum or min)) and (((IC or (integrated adj1 circuit) or circuit or VLSI or LSI) same (design\$3 or model\$3 or similat\$3)) and ((worst or pessimistic or maximum or max) same (optimistic or minimum or min)))))) | USPAT; US-PGPUB; EPO; JPO; DERWENT | 2004/02/04 08:12 |
| - | 512 | ((compar\$3 or discriminat\$3 or differen\$5) with (resistance or capacitance or impendance or power) with (threshold or constraint or standard or predetermin\$5)) and (((compar\$3 or discriminat\$3 or differen\$5) same (resistance or capacitance or impendance or power) same (threshold or constraint or standard or predetermin\$5)) and (((compar\$3 or discriminat\$3 or differen\$5) same (resistance or capacitance or impendance or power)) and (((compar\$3 or discriminat\$3 or differen\$5) same (worst or pessimistic or maximum or max) same (optimistic or minimum or min)) and (((IC or (integrated adj1 circuit) or circuit or VLSI or LSI) same (design\$3 or model\$3 or similat\$3)) and ((worst or pessimistic or maximum or max) same (optimistic or minimum or min)))))) | USPAT; US-PGPUB; EPO; JPO; DERWENT | 2004/02/04 08:00 |
| - | 33 | ((leaf or relat\$3 or depend\$4) near2 (cell or portion)) and (((compar\$3 or discriminat\$3 or differen\$5) with (resistance or capacitance or impendance or power) with (threshold or constraint or standard or predetermin\$5)) and (((compar\$3 or discriminat\$3 or differen\$5) same (resistance or capacitance or impendance or power) same (threshold or constraint or standard or predetermin\$5)) and (((compar\$3 or discriminat\$3 or differen\$5) same (resistance or capacitance or impendance or power)) and (((compar\$3 or discriminat\$3 or differen\$5) same (worst or pessimistic or maximum or max) same (optimistic or minimum or min)) and (((IC or (integrated adj1 circuit) or circuit or VLSI or LSI) same (design\$3 or model\$3 or similat\$3)) and ((worst or pessimistic or maximum or max) same (optimistic or minimum or min)))))) | USPAT; US-PGPUB; EPO; JPO; DERWENT | 2004/02/04 08:09 |

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| - | 24 | ((compar\$3 or discriminat\$3 or differen\$5) same (label\$3 or categoriz\$3 or tag\$4 or mark\$3 or indicat\$3)) and ((label\$3 or categoriz\$3 or tag\$4 or mark\$3 or indicat\$3) and (((leaf or relat\$3 or depend\$4) near2 (cell or portion)) and (((compar\$3 or discriminat\$3 or differen\$5) with (resistance or capacitance or impendance or power) with (threshold or constraint or standard or predetermin\$5)) and (((compar\$3 or discriminat\$3 or differen\$5) same (resistance or capacitance or impendance or power) same (threshold or constraint or standard or predetermin\$5)) and (((compar\$3 or discriminat\$3 or differen\$5) same (resistance or capacitance or impendance or power)) and (((compar\$3 or discriminat\$3 or differen\$5) same (worst or pessimistic or maximum or max) same (optimistic or minimum or min)) and (((IC or (integrated adj1 circuit) or circuit or VLSI or LSI) same (design\$3 or model\$3 or similat\$3)) and ((worst or pessimistic or maximum or max) same (optimistic or minimum or min)))))))))) | USPAT; US-PGPUB; EPO; JPO; DERWENT | 2004/02/04 12:44 |
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